

**Physics 198, Spring Semester 1999**  
**Introduction to Radiation Detectors and Electronics**

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Problem Set 10: Due on Tuesday, 13-Apr-99 at begin of lecture.

Discussion on Wednesday, 14-Apr-99 at 12 – 1 PM in 347 LeConte.

Office hours: Mondays, 3 – 4 PM in 420 LeConte

1. Traps in semiconductor materials are often characterized by a lifetime  $\tau$ . A packet of charge subject to trapping will decay with time as

$$Q(t) = Q_0 e^{-t/\tau}$$

- a) In an electric field  $E$  the charge will drift. What is the charge remaining after drifting a distance  $x$ ?
- b) The parameter  $\mu E \tau$  is the trapping (or recombination) length  $L$ . In a detector with depletion width  $d$ , what is the induced signal charge as a function of  $d$  and  $L$ ? Consider only the carrier type subject to trapping/recombination.
- c) If  $d \gg L$ , what is the induced signal charge? How thick must the detector be for the induced charge to be 95% of the deposited charge?
2. A Si detector diode with  $1 \text{ cm}^2$  area has a reverse bias current of 1 nA at a temperature of  $20 \text{ }^\circ\text{C}$ .
- a) Under forward bias, how much voltage is required to obtain a current of 1 mA?
- b) On the same wafer there is a second identical diode, except that its diameter is  $100 \text{ }\mu\text{m}$ . How large is its reverse bias current?
- c) How much forward bias voltage on the small diode is required for a current of 1 mA? How much voltage is required after cooling the diode to  $-20 \text{ }^\circ\text{C}$ ?
3. A radiation damaged detector has a reverse bias current of  $1 \text{ }\mu\text{A}$  at  $100 \text{ }\mu\text{m}$  depletion width. The operating temperature is  $20 \text{ }^\circ\text{C}$ .
- a) The detector is still partially depleted after quadrupling the bias voltage. How large is the reverse bias current?
- b) What is the detector current when the temperature is decreased from  $20 \text{ }^\circ\text{C}$  to  $-10 \text{ }^\circ\text{C}$ ?

Turn page for Problem 4.

4. A spectroscopy system using a Si diode at room temperature (20 °C) exhibits an equivalent noise charge of 200 eV at the optimum shaping time of 1  $\mu$ s.
- How large are the noise contributions (in eV) due to current and voltage noise?
  - Assuming that the current noise is dominated by the reverse bias current of the detector, what is the total noise when the detector is cooled to liquid nitrogen temperature?
  - If the detector is cooled to -20 °C, what is the optimum shaping time? Assume  $F_i = F_v = 1$ . What is the corresponding noise level?